

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1232	Aug-96	9624 C1	ANAM, PI.	DK615596ABB	3.0μ OX/NI	08 PDIP

STRESS/JOB NO.

READPOINT (Sample Size/No. of Fails)

Infant / High Voltage Life 125°C, 7.0 V. P-17995, P-18038	<table border="0"> <tr> <td><u>48 Hr</u></td> <td><u>336 Hr</u></td> <td><u>1KHr</u></td> <td><u>*Failure Rate</u></td> </tr> <tr> <td>231/0</td> <td>77/0</td> <td>77/0</td> <td>30 Fits</td> </tr> </table>	<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>	231/0	77/0	77/0	30 Fits
<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>						
231/0	77/0	77/0	30 Fits						

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle -55°C to +125°C P-18039	<table border="0"> <tr> <td><u>300 ~</u></td> <td><u>1K ~</u></td> <td><u>Cum %</u></td> </tr> <tr> <td>39/0</td> <td>39/0</td> <td>0.0%</td> </tr> </table>	<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>	39/0	39/0	0.0%
<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>					
39/0	39/0	0.0%					

Biased Moisture (HAST) 120°C/85% RH, 5.5 V. P-18040	<table border="0"> <tr> <td><u>100 Hr</u></td> <td><u>Cum %</u></td> </tr> <tr> <td>77/0</td> <td>0.0%</td> </tr> </table>	<u>100 Hr</u>	<u>Cum %</u>	77/0	0.0%
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77/0	0.0%				

Autoclave 121°C/100% RH, 2 Atmos P-18041	<table border="0"> <tr> <td><u>96 Hr</u></td> <td><u>Cum %</u></td> </tr> <tr> <td>38/0</td> <td>0.0%</td> </tr> </table>	<u>96 Hr</u>	<u>Cum %</u>	38/0	0.0%
<u>96 Hr</u>	<u>Cum %</u>				
38/0	0.0%				

Failure Mode

Failure Analysis